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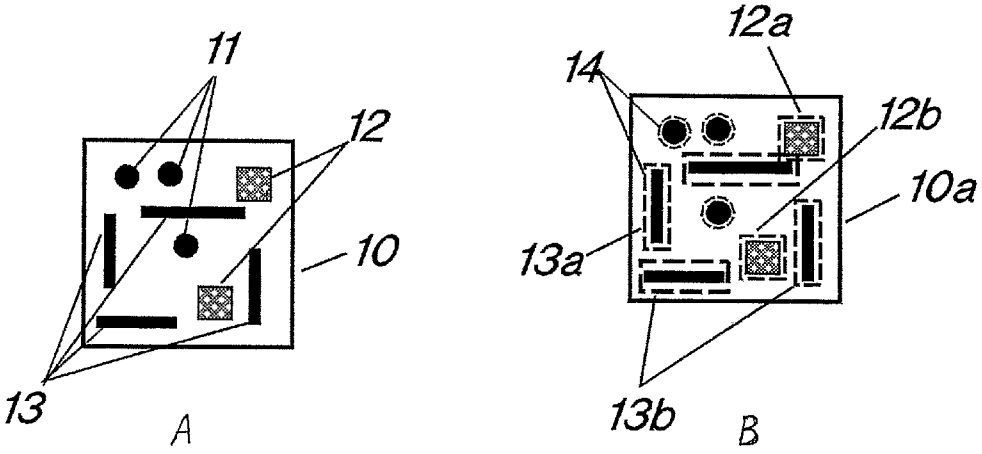
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(54) **Title:** A METHOD AND A SYSTEM FOR ESTABLISHING AN INSPECTION RECIPE



(57) **Abstract:** A method and a system for establishing a wafer testing recipe are disclosed. According to the present invention the system is comprised of a camera for acquiring images of a number of dice from a produced wafer; and a dedicated software that operative for using at least part of the images and composes a reference-image to be used as testing reference of a typical die image; defining on the reference-image single and/or repeatable elements of a die pattern as a "zone of interest; determining the Detection-Policy for each of the zone of interest or for a group of similar zones of interest and determining the algorithm that will be used by each of the Detection-Policy; determining the parameters of each of the Detection-Policy's algorithms; determining the Reporting-policy by defining a set of specific names of defect classes that could be used during inspection of a specific lot of wafers; determining the Inspection-policy defining behavior of inspection system as a set of pre-defined logical rules; and creating a "wafer testing recipe" by integrating of the testing reference of a typical die image, the defined zones of interest, the determined Detection-Policies, the parameters of the determined Detection-Policies' algorithms, the determined Reporting-Policies and the determined Inspection-Policies.

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